

Search Notes

Application/Control No.

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Examiner

Fred I. Ehichioya

Applicant(s)/Patent under
Reexamination

CHEN ET AL.

Art Unit

2162

SEARCHED

Class	Subclass	Date	Examiner
707	1, 2, 3, 5, 101, 104.1	6/11/2005	FE
703	27	6/11/2005	FE
706	23	6/11/2005	FE
709	203, 223	6/11/2005	FE
713	176	6/11/2005	FE

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East Search	6/11/2005	FE
IEEE Xplore Search	6/11/2005	FE
ACM Digital Library Search	6/11/2005	FE